Search Notes



Application/Control No.	
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Applicant(s)/Patent under Reexamination OGAWA, HIDEHIKO

Art Unit

Thomas D. Lee

Examiner

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	SEARCHED					
Class	Subclass	Date	Examiner			
358	1.15, 402, 440	6/6/2005	TDL			
379	100.01	6/6/2005	TDL			
379	100.08	6/6/2005	TDL			
379	100.13	6/6/2005	TDL			
379	100.17	6/6/2005	TDL			

INTERFERENCE SEARCHED						
Subclass	Date	Examiner				
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